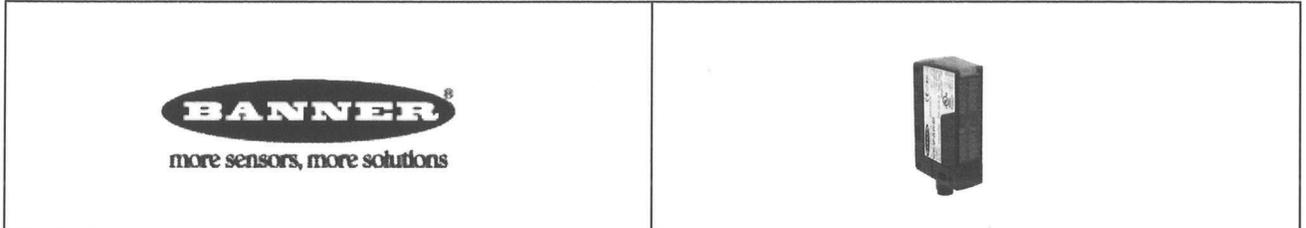




# Device Test Report

Device Test System Revision : 3.1.1.4 Build: 2020-9-2 Test ID:653046495



Vendor : Banner Engineering Corporation

Device Name : Q76E IO-Link

Vendor ID : 0x01C3

Device ID : 0x071301

IO-Link Version : 1.1

Product ID : Q76E

ISDU supported : False

SIO mode supported : True

Process Data Input Bits : 8

Process Data Output Bits : 1

Min Cycle Time : 2300 µs

Bitrate : COM2

Implemented Access Locks :

parameter="False" datastorage="False" localParameterization="False" localUserInterface="False"

IODD : Banner\_Engineering-Q76E-KP-ZLVC-Q5-20200801-IODD1.1.xml

Checker : IODD-Checker V1.1.4

CRC : 705090584

Firmware Revision : not known

Hardware Revision : not known

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Test result : All test were passed with positiv result in complete operation

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Test operated by :

Company : Banner Engineering

Name : Paul Fabian

Signature : 

Cover Sheet Page 1



**Testreport Overview (1)**

TC_Device_Identification	ok
Data Layer Tests V1.0.3.52	
SDCI_TC_0034 TCD_DLPC_STUP_CYCTIME	ok
SDCI_TC_0035 TCD_DLPC_STUP_STUPOPER1	ok
SDCI_TC_0036 TCD_DLPC_STUP_STUPOPER2	ok
SDCI_TC_0037 TCD_DLPC_OPER_OPERSTUP1	ok
SDCI_TC_0038 TCD_DLPC_STAR_OPERSTAR2	ok
SDCI_TC_0039 TCD_DLPC_PREO_READDPP1	ok
SDCI_TC_0040 TCD_DLPC_PREO_WRITEDPP1	ok
SDCI_TC_0041 TCD_DLPC_PROP_SHORT_FRAME	ok
SDCI_TC_0043 TCD_DLPC_PROP_SIMRESET	ok
SDCI_TC_0044 TCD_DLPC_PROP_FRAMEFAULT	ok
SDCI_TC_0045 TCD_DLPC_OPER_READ	ok
SDCI_TC_0046 TCD_DLPC_OPER_WRITE	ok
SDCI_TC_0047 TCD_DLPC_OPER_NEGWRITE	ok
SDCI_TC_0049 TCD_DLPC_OPER_SIMRESET	ok
SDCI_TC_0306 TCD_DLPC_CHCK_OVERRIDOK	ok
ISDU Tests V1.0.3.52	
Event Tests V1.0.3.52	
SDCI_TC_0069 TCD_DLIC_EVNT_OPERSINGLEEVENT	ok
SDCI_TC_0070 TCD_DLIC_EVNT_PROPSINGLEEVENT	ok
SDCI_TC_0071 TCD_DLIC_EVNT_OPEREVENTCLEAR	ok
SDCI_TC_0072 TCD_DLIC_EVNT_OPERCOMMINTERRUPT	ok
SDCI_TC_0073 TCD_DLIC_EVNT_OPERPOWERINTERRUPT	ok
SDCI_TC_0074 TCD_DLIC_EVNT_OPERAPPEARDISAPPEAR	ok
SDCI_TC_0075 TCD_DLIC_EVNT_OPERMULTEVENT	ok
SDCI_TC_0076 TCD_DLIC_EVNT_OPERSHORTEVENT	ok
Data Storage Tests V1.0.3.52	
Legacy Master Tests V1.0.3.52	
SDCI_TC_0085 TCD_DLIC_COMP_STARTUP	ok
SDCI_TC_0086 TCD_DLIC_COMP_TYPE1INTERLEAVE	ok
SDCI_TC_0087 TCD_DLIC_COMP_PDINVALIDEVENT	ok
Direct Parameter Page 1 Tests V1.0.3.52	
SDCI_TC_0089 TCD_DLPC_STDP_MASTERCYCLETIME	ok
SDCI_TC_0090 TCD_DLPC_STDP_MINCYCLETIME	ok
SDCI_TC_0091 TCD_DLPC_STDP_FSEQCAPABILITY	ok
SDCI_TC_0092 TCD_DLPC_STDP_REVISIONID	ok
SDCI_TC_0093 TCD_DLPC_STDP_PDIN	ok
SDCI_TC_0094 TCD_DLPC_STDP_PDOUT	ok
SDCI_TC_0095 TCD_DLPC_STDP_VENDORID	ok
SDCI_TC_0096 TCD_DLPC_STDP_DEVICEID	ok
SDCI_TC_0097 TCD_DLPC_STDP_FUNCTIONID	ok

**Testreport Overview (2)**

SDCI_TC_0100 TCD_DLPC_STDP_READRESPAR	ok
SDCI_TC_0101 TCD_DLPC_STDP_WRITERESPAR	ok
Predefined Device Parameter Tests V1.0.3.52	
Block Parameter Tests V1.0.3.52	
IODD based Tests V1.0.3.52	
SDCI_TC_0149 TCD_IODD_PARV_IDENT	ok
SDCI_TC_0150 TCD_IODD_PARV_COMPROFILE	ok
SDCI_TC_0151 TCD_IODD_PARV_READVERIFY	ok
SDCI_TC_0152 TCD_IODD_PARV_WRITEVERIFY	ok
SDCI_TC_0155 TCD_IODD_PARV_FACTORYSETTINGS	ok
SDCI_TC_0156 TCD_IODD_PARV_ACCESSLOCK	ok
SDCI_TC_0157 TCD_IODD_PARV_INDEXCONSISTENT	ok
support of Physical Layer Tests V1.0.3.52	
SDCI_TC_0304 TCD_PHYL_INTF_UARTTRANSDelay	ok
SDCI_TC_0305 TCD_PHYL_INTF_RESPONSETIME	ok

## Test Report Statistics:

Number of test cases overall : 47  
Number of test cases ok : 47  
Number of test cases failed : 0  
Number of test cases skipped : 0  
Test Operation : complete